

RoHS Compliant Product
A suffix of "C" specifies halogen and lead-free

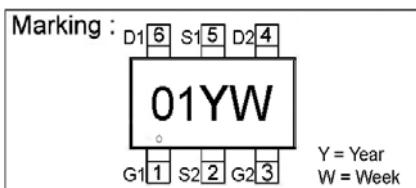
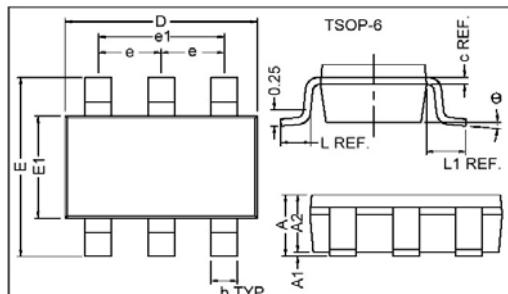
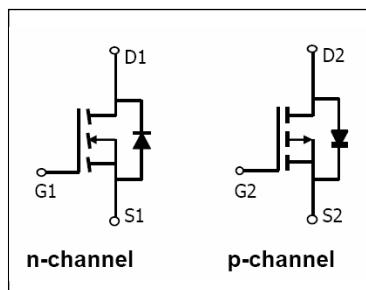
DESCRIPTION

The STT6601 is the N and P Channel enhancement mode power FET produced using high cell-density, DMOS trench technology. This high density process is especially tailored to minimize on-state resistance and provide superior switching performance. These devices are particularly suited for low voltage applications such as notebook computer power management and other battery-powered circuits where high-side switching, low in-line power loss and resistance to transients are needed.

FEATURES

- N-Channel
 - 30V/2.8A, $R_{DS(ON)} = 68\text{m}\Omega$ @ $VGS = 10\text{ V}$
 - 30V/2.3A, $R_{DS(ON)} = 78\text{m}\Omega$ @ $VGS = 4.5\text{ V}$
 - 30V/1.5A, $R_{DS(ON)} = 108\text{m}\Omega$ @ $VGS = 2.5\text{ V}$
- P-Channel
 - 30V/-2.8A, $R_{DS(ON)} = 105\text{m}\Omega$ @ $VGS = 10\text{ V}$
 - 30V/-2.5A, $R_{DS(ON)} = 120\text{m}\Omega$ @ $VGS = 4.5\text{ V}$
 - 30V/-1.5A, $R_{DS(ON)} = 150\text{m}\Omega$ @ $VGS = 2.5\text{ V}$
- Super high density cell design for extremely low $R_{DS(ON)}$
- Exceptional on-resistance and maximum DC current capability
- TSOP-6P package design

PACKAGE DIMENSIONS



Week code: A~Z (1~26); a ~ z (27 ~ 52)

REF.	Millimeter		REF.	Millimeter	
	Min.	Max.		Min.	Max.
A	1.10	Max	L	0.45	Ref
A1	0	0.10	L1	0.60	Ref
A2	0.70	1.00		0°	10°
c	0.12	Ref	b	0.30	0.50
D	2.70	3.10	e	0.95	Ref
E	2.60	3.00	e1	1.90	Ref
E1	1.40	1.80			

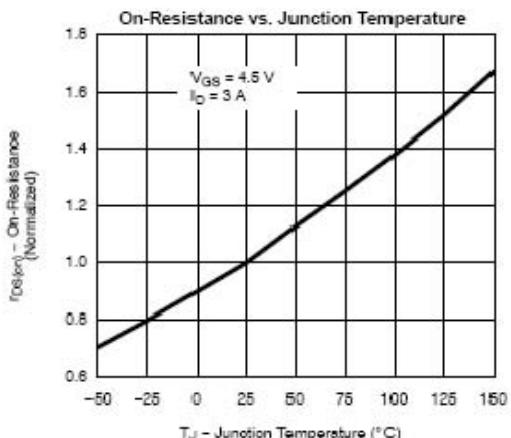
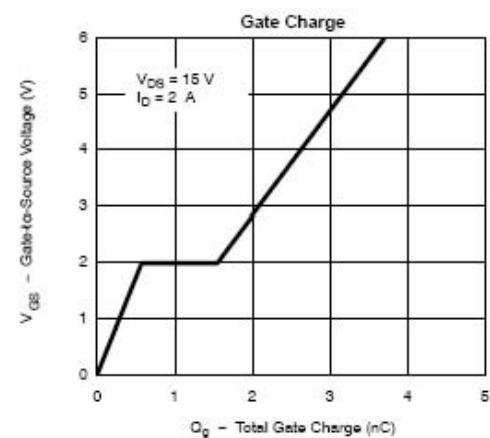
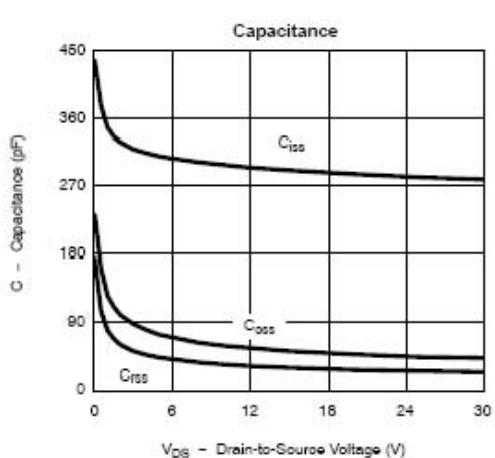
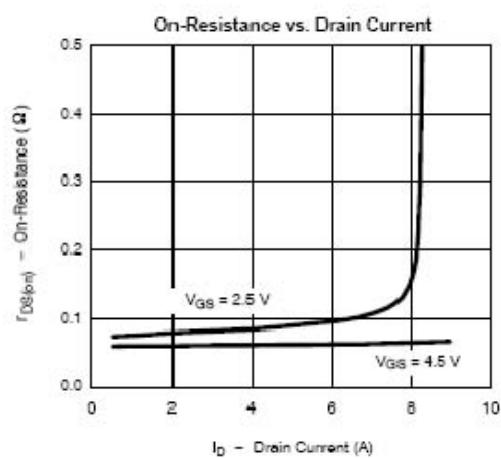
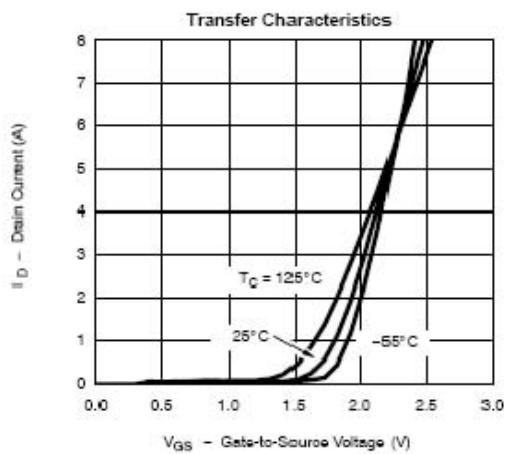
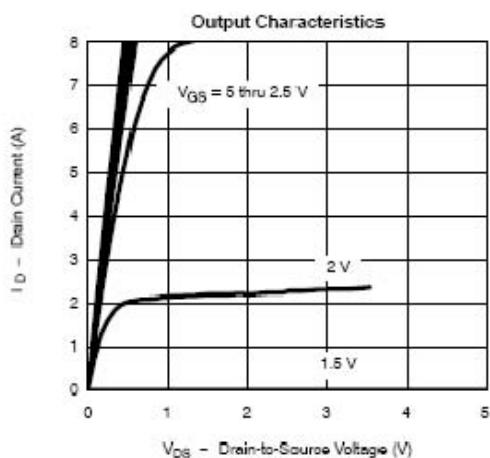
ABSOLUTE MAXIMUM RATINGS

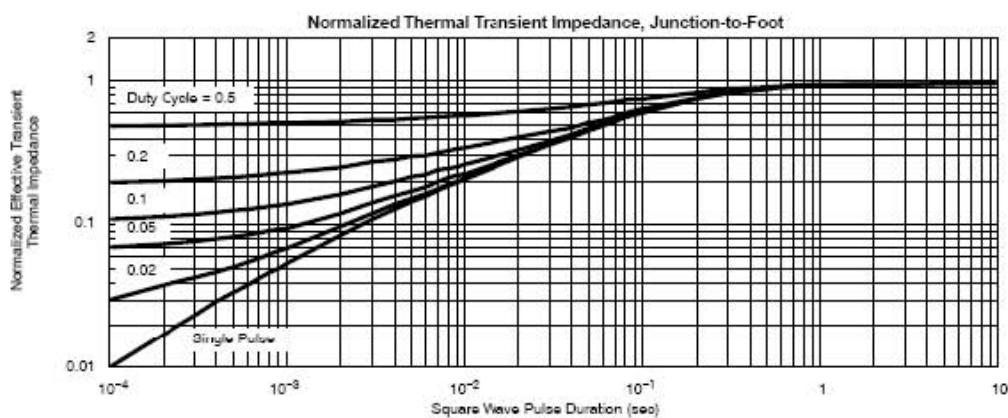
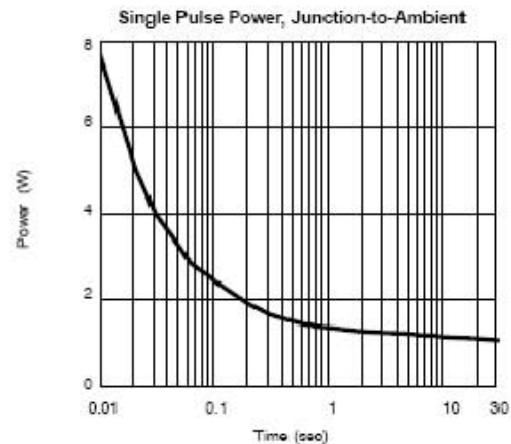
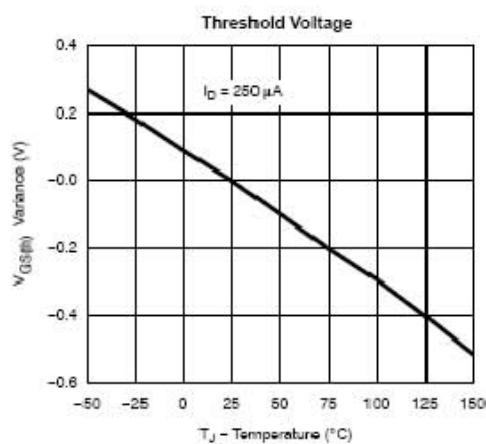
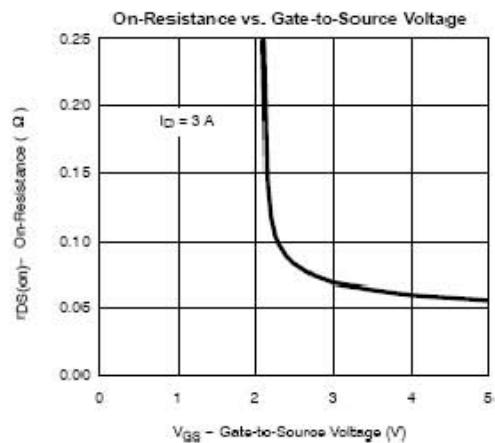
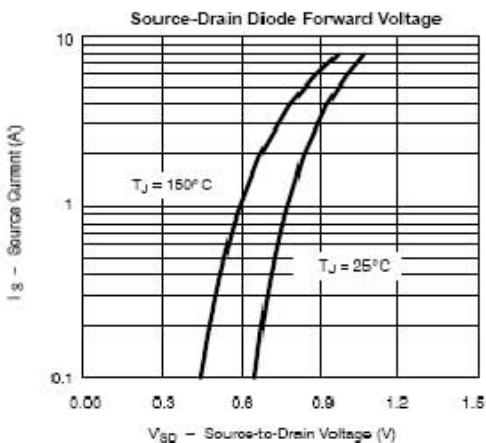
Parameter	Symbol	Ratings		Unit
		N-Channel	P-Channel	
Drain-Source Voltage	V_{DS}	30	-30	V
Gate-Source Voltage	V_{GS}	± 12	± 12	V
Continuous Drain Current ($T_J=150^\circ\text{C}$)	$I_D @ T_A=25^\circ\text{C}$	2.8	-2.8	A
	$I_D @ T_A=70^\circ\text{C}$	2.3	-2.1	
Pulsed Drain Current	I_{DM}	10	-8	A
Power Dissipation	$P_D @ T_A=25^\circ\text{C}$	1.15		W
	$P_D @ T_A=70^\circ\text{C}$	0.75		
Continuous Source Current (Diode Conduction)	I_S	1.25	-1.4	A
Thermal Resistance- Junction to Ambient $T \leq 10\text{ sec}$ Steady State	$R_{\theta JA}$	50	52	$^\circ\text{C}/\text{W}$
		90	90	
Operating Junction and Storage Temperature Range	T_J, T_{STG}	-55 ~ +150		°C

ELECTRICAL CHARACTERISTICS (T_A = 25°C unless otherwise specified)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Drain-Source Breakdown Voltage	N-Ch	BV _{DSS}	30	-	-	V _{GS} =0, I _D =250μA
			-30	-	-	
Gate Threshold Voltage	N-Ch	V _{GS(th)}	0.8	-	1.6	V _{DS} =V _{GS} , I _D =250μA
			-0.4		-1.0	
Forward Transconductance	N-Ch	g _{fs}	-	4.6	-	V _{DS} =4.5V, I _D =-6.0A
			-	4	-	
Gate Leakage Current	N-Ch	I _{GSS}	-	-	±100	nA
			-	-	±100	
Zero Gate Voltage Drain Current (T _j =25°C)	N-Ch	I _{DSS}	-	-	1	V _{DS} =24 V, V _{GS} =0 V
	P-Ch		-	-	-1	
	N-Ch		-	-	10	
	P-Ch		-	-	-10	
On-State Drain Current	N-Ch	I _{D(on)}	6	-	-	V _{DS} ≥ 5V, V _{GS} =10 V
	P-Ch		-6	-	-	
Drain-Source On-Resistance	N-Ch	R _{DS(ON)}	-	0.048	0.068	Ω
	P-Ch		-	0.077	0.105	
	N-Ch		-	0.054	0.078	
	P-Ch		-	0.092	0.120	
	N-Ch		-	0.079	0.108	
	P-Ch		-	0.118	0.150	
Total Gate Charge	N-Ch	Q _g	-	4.2	6	nC
	P-Ch		-	5.8	-	
Gate-Source Charge	N-Ch	Q _{gs}	-	0.6	-	
	P-Ch		-	0.8	-	
Gate-Drain Charge	N-Ch	Q _{gd}	-	1.5	-	
	P-Ch		-	1.5	-	
Turn-on Time	N-Ch	T _{d(on)}	-	2.5	-	
	P-Ch		-	6	-	
Turn-off Time	N-Ch	T _r	-	2.5	-	ns
	P-Ch		-	3.9	-	
Turn-off Time	N-Ch	T _{d(off)}	-	20	-	
	P-Ch		-	40	-	
Turn-off Time	N-Ch	T _f	-	4	-	
	P-Ch		-	15	-	

CHARACTERISTIC CURVES (N-Channel)





CHARACTERISTIC CURVES (N-Channel)

